

Shear Force Microscopy

K. P. Leija-Alfárez,^a G. A. Martínez-Zepeda,^b O. Ruiz-Cigarrillo,^c and L. F. Lastras-Martínez^d

Instituto de Investigacion en Comunicación Óptica, Universidad Autonoma de San Luis Potosí

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This work exposes the first results of an important way to make superficial Microscopy, taking the diffraction limit as fundamental physics. In this experimental area is common, Atomic Force Microscopy (AFM), and even though the objective of this work is to get the resolution of AFM, the first results are very interesting. Frequently, in the atomic tomography of surfaces, the AFM gets the kingdom, but in this system, it's possible to pass from microns to the nanometric resolution taking the advantage of artisanal construction.

^a a236792@alumnos.uaslp.mx

^b gabmtzz27@gmail.com

^c oscarruiz@cactus.iico.uaslp.mx

^d lflm@cactus.iico.uaslp.mx